

Scanning Electron Microscopy and Nanomaterials Characterisation

Laboratory and Research

Course Overview

Scanning Electron Microscopy and Nanomaterials Characterisation: a 5-day professional training course from LTC Consultants, delivered in-classroom across...

What You Will Achieve

- Explain the core principles and current good practice in Scanning Electron Microscopy and Nanomaterials Characterisation
- Apply practical tools and techniques for Scanning Electron Microscopy and Nanomaterials Characterisation in your own organisation
- Analyse real-world scenarios and select the right approach with confidence
- Avoid the common pitfalls that undermine Scanning Electron Microscopy and Nanomaterials Characterisation in practice
- Build a personal action plan to implement what you have learned

Who Should Attend

Professionals, specialists and managers at every level who want to strengthen this capability and apply it with confidence at work.

Course Outline

1. Foundations of Scanning Electron Microscopy and Nanomaterials Characterisation: principles, terminology and context
2. The business case: why Scanning Electron Microscopy and Nanomaterials Characterisation matters to performance
3. Core tools, frameworks and methods
4. Applying the tools: guided case study and exercises
5. Common pitfalls and how experienced practitioners avoid them
6. Working with stakeholders: communication and influence
7. Measuring results and continuous improvement
8. Personal action planning and course review

Upcoming Dates and Fees

DATES	VENUE	FEE (PER DELEGATE)
2 to 6 Nov 2026	Maputo	\$1,450
9 to 13 Nov 2026	Johannesburg	\$1,650
16 to 20 Nov 2026	Cape Town	\$1,550

23 to 27 Nov 2026	Nairobi	\$1,550
30 Nov to 4 Dec 2026	Kampala	\$1,450
7 to 11 Dec 2026	Durban	\$1,450

LTC Consultants

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Every delegate receives a Certificate of Attendance. Group and in-house rates available on request.